

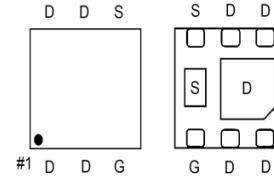
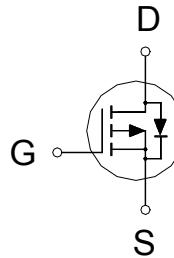
**NIKO-SEM**

# P-Channel Enhancement Mode Field Effect Transistor

**PB521BX**  
PDFN 2x2S  
Halogen-Free & Lead-Free

**PRODUCT SUMMARY**

$V_{(BR)DSS}$	$R_{DS(ON)}$	$I_D$
-20V	21mΩ	-8A



G : GATE  
D : DRAIN  
S : SOURCE

**ABSOLUTE MAXIMUM RATINGS ( $T_A = 25^\circ\text{C}$  Unless Otherwise Noted)**

PARAMETERS/TEST CONDITIONS	SYMBOL	LIMITS	UNITS
Drain-Source Voltage	$V_{DS}$	-20	V
Gate-Source Voltage	$V_{GS}$	$\pm 10$	V
Continuous Drain Current $T_A = 25^\circ\text{C}$	$I_D$	-8	A
$T_A = 70^\circ\text{C}$	$I_D$	-6.4	
Pulsed Drain Current <sup>1</sup>	$I_{DM}$	29	
Power Dissipation $T_A = 25^\circ\text{C}$	$P_D$	2.1	W
$T_A = 70^\circ\text{C}$	$P_D$	1.4	
Operating Junction & Storage Temperature Range	$T_j, T_{stg}$	-55 to 150	°C

**THERMAL RESISTANCE RATINGS**

THERMAL RESISTANCE	SYMBOL	TYPICAL	MAXIMUM	UNITS
Junction-to-Ambient <sup>2</sup>	$R_{\theta JA}$		57	°C/W

<sup>1</sup>Pulse width limited by maximum junction temperature.

<sup>2</sup>The value of  $R_{\theta JA}$  is measured with the device mounted on 1in<sup>2</sup> FR-4 board with 2oz. Copper.

**ELECTRICAL CHARACTERISTICS ( $T_j = 25^\circ\text{C}$ , Unless Otherwise Noted)**

PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNIT
			MIN	TYP	MAX	
<b>STATIC</b>						
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS} = 0V, I_D = -250\mu\text{A}$	-20			V
Gate Threshold Voltage	$V_{GS(\text{th})}$	$V_{DS} = V_{GS}, I_D = -250\mu\text{A}$	-0.45	-0.6	-0.85	
Gate-Body Leakage	$I_{GSS}$	$V_{DS} = 0V, V_{GS} = \pm 10V$			$\pm 100$	nA
Zero Gate Voltage Drain Current	$I_{DSS}$	$V_{DS} = -16V, V_{GS} = 0V$			-1	$\mu\text{A}$
		$V_{DS} = -10V, V_{GS} = 0V, T_j = 55^\circ\text{C}$			-10	
Drain-Source On-State Resistance <sup>1</sup>	$R_{DS(\text{ON})}$	$V_{GS} = -1.8V, I_D = -1\text{A}$		24	40	$\text{m}\Omega$
		$V_{GS} = -2.5V, I_D = -2\text{A}$		19	28	
		$V_{GS} = -4.5V, I_D = -2.5\text{A}$		15	21	
Forward Transconductance <sup>1</sup>	$g_{fs}$	$V_{DS} = -10V, I_D = -2.5\text{A}$		21		S

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DYNAMIC						
Input Capacitance	$C_{iss}$	$V_{GS} = 0V, V_{DS} = -10V, f = 1MHz$	1727			pF
Output Capacitance	$C_{oss}$		179			
Reverse Transfer Capacitance	$C_{rss}$		155			
Gate Resistance	$R_g$	$V_{GS} = 0V, V_{DS} = 0V, f = 1MHz$	10			$\Omega$
Total Gate Charge <sup>2</sup>	$Q_g$	$V_{DS} = -10V, V_{GS} = -4.5V, I_D = -2.5A$	21			nC
Gate-Source Charge <sup>2</sup>	$Q_{gs}$		1.8			
Gate-Drain Charge <sup>2</sup>	$Q_{gd}$		4.9			
Turn-On Delay Time <sup>2</sup>	$t_{d(on)}$	$V_{DD} = -10V$ $I_D \geq -2.5A, V_{GEN} = -4.5V, R_G = 6\Omega$	28			nS
Rise Time <sup>2</sup>	$t_r$		21			
Turn-Off Delay Time <sup>2</sup>	$t_{d(off)}$		81			
Fall Time <sup>2</sup>	$t_f$		48			
SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS ( $T_J = 25^\circ C$ )						
Continuous Current	$I_S$				-1.7	A
Forward Voltage <sup>1</sup>	$V_{SD}$	$I_F = -2.5A, V_{GS} = 0V$			-1.2	V
Reverse Recovery Time	$t_{rr}$	$I_F = -2.5A, dI_F/dt = 100A / \mu S$	35			nS
Reverse Recovery Charge	$Q_{rr}$		18			nC

<sup>1</sup>Pulse test : Pulse Width  $\leq 300 \mu sec$ , Duty Cycle  $\leq 2\%$ .

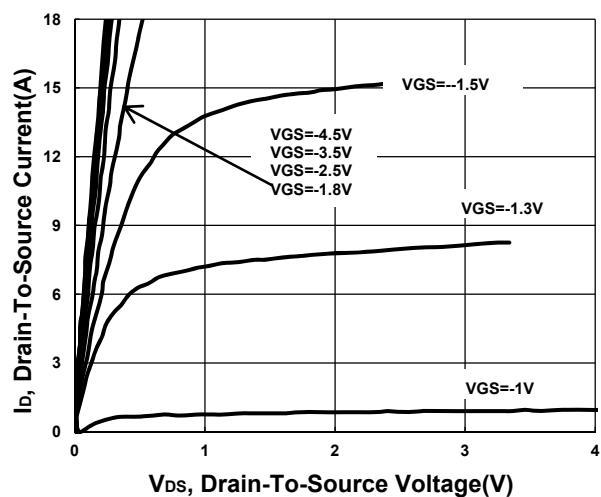
<sup>2</sup>Independent of operating temperature.

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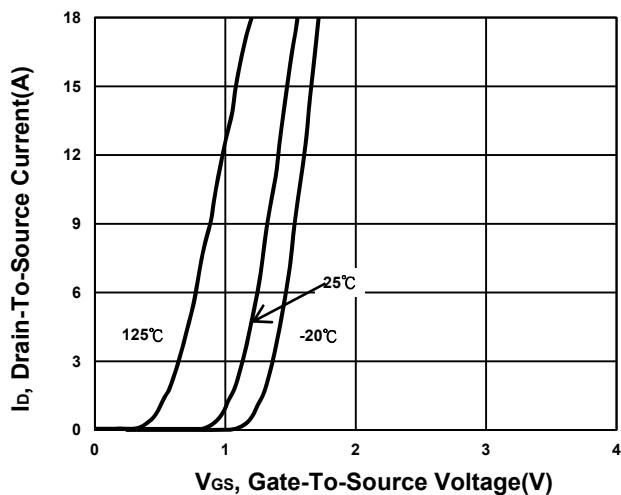
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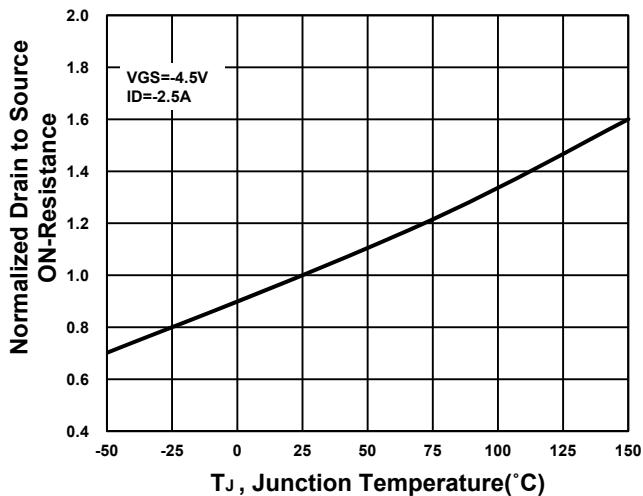
**Output Characteristics**



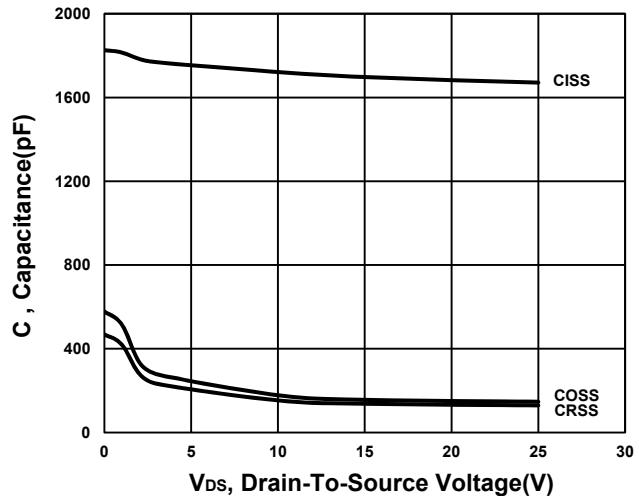
**Transfer Characteristics**



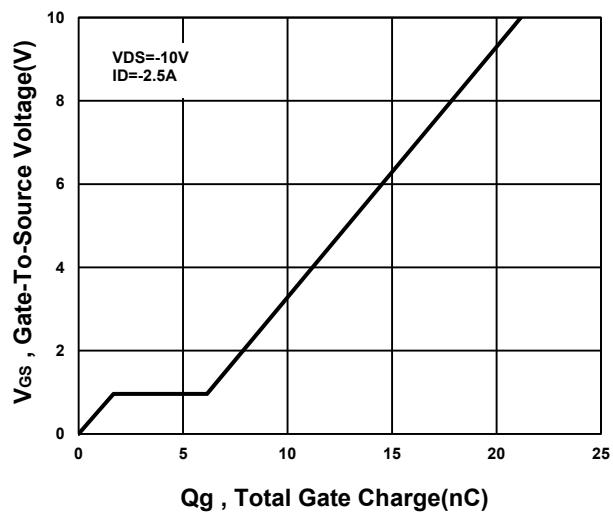
**On-Resistance VS Temperature**



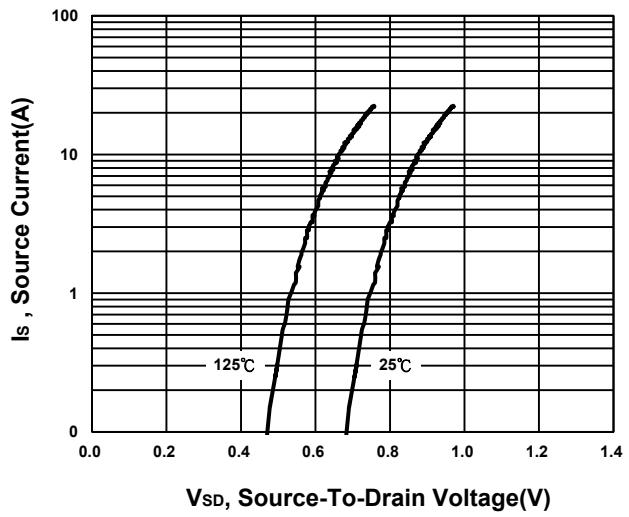
**Capacitance Characteristic**



**Gate charge Characteristics**



**Source-Drain Diode Forward Voltage**

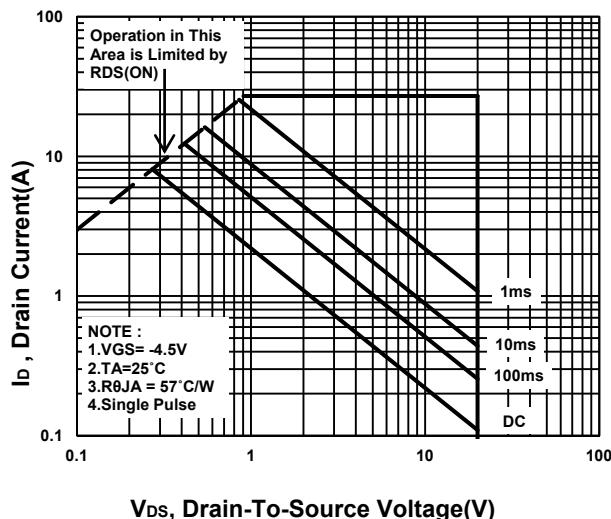


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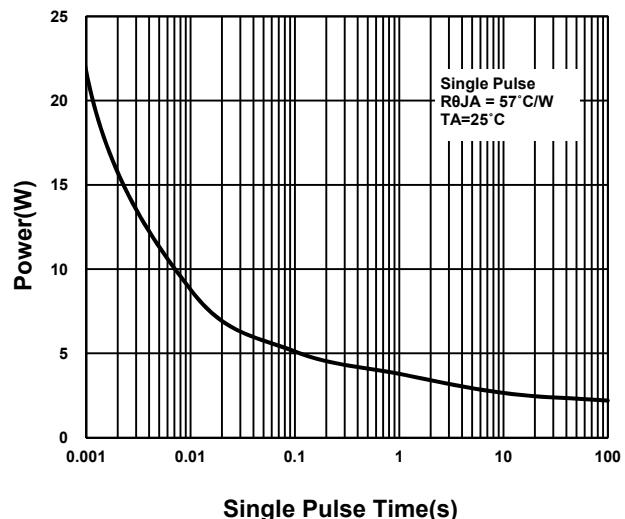
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**Safe Operating Area**



**Single Pulse Maximum Power Dissipation**



**Transient Thermal Response Curve**

